

Performance of the Planar AlGa_{0.25}GaN/GaN Bow-Tie Diodes Developed for Terahertz Detection

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A compact and sensitive terahertz (THz) detector with a fast response time is highly desired for the THz imaging systems operating at the room temperature. Unique physical properties of gallium nitride (GaN) have triggered a breakthrough for the next generation of the THz electronic components [1–3].

In this work, performance of the AlGa_{0.25}GaN/GaN bow-tie (BT) diodes developed for THz detection is reported. The BT diodes were developed on two Al_{0.25}Ga_{0.75}N/GaN high electron mobility transistor (HEMT) structures grown on semi-insulating SiC substrates. HEMT structures slightly differed in the 2DEG sheet resistance values: about 430 Ω/sq. and 330 Ω/sq. for the samples S1 and S2, respectively. The sub-THz performance was studied considering the variation of the apex width of the BT diode. Response was studied at discrete microwave (9-11 GHz) and sub-THz frequencies (150-600 GHz). The current voltage characteristics measured in dc- and pulsed regimes were also investigated. The results demonstrated a new potential of AlGa_{0.25}GaN/GaN HEMT structures for applications in sub-THz frequencies.

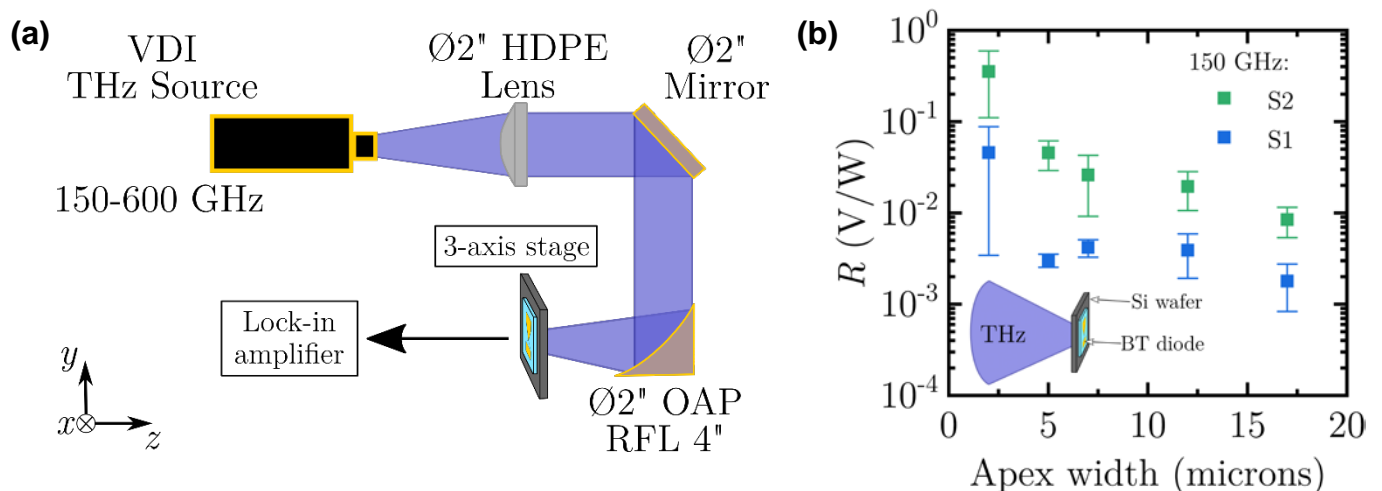


Fig. 1 (a) Setup of sub-THz detection experiment; (b) Responsivity R of the AlGa_{0.25}GaN/GaN BT diodes as a function of apex width at a frequency of 150 GHz.

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